UNISONIC TECHNOLOGIES CO., LTD

12N60-C **Power MOSFET**

12A, 600V N-CHANNEL **POWER MOSFET**

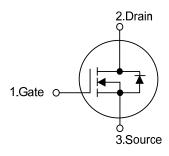
DESCRIPTION

The UTC 12N60-C is a high voltage power MOSFET designed to have better characteristics, such as fast switching time, low gate charge, low on-state resistance and high rugged avalanche characteristics. This power MOSFET is usually used in high speed switching applications of switching power supplies and adaptors.

FEATURES

- * $R_{DS(ON)}$ < 0.7 Ω @ V_{GS} = 10 V, I_{D} = 6.0 A
- * Fast switching capability
- * Avalanche energy tested
- * Improved dv/dt capability, high ruggedness

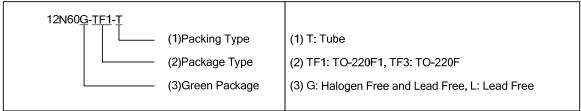
SYMBOL



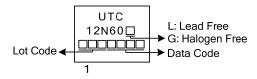
ORDERING INFORMATION

Ordering Number		Dookago	Pin	Dooking			
Lead Free	Halogen Free	- Package	1	2	3	Packing	
12N60L-TF1-T	12N60G-TF1-T	TO-220F1	G	D	S	Tube	
12N60L-TF3-T	12N60G-TF3-T	TO-220F	G	D	S	Tube	

Note: Pin Assignment: G: Gate D: Drain S: Source



MARKING



TO-220 TO-220F1

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■ **ABSOLUTE MAXIMUM RATINGS** (T_C = 25°C, unless otherwise specified)

PARAMETER		SYMBOL	RATINGS	UNIT
Drain-Source Voltage		V_{DSS}	600	V
Gate-Source Voltage		V_{GSS}	±30	V
Continuous Drain Current		I_{D}	12	Α
Pulsed Drain Current (Note 2)		I_{DM}	48	Α
Avalanche Energy	Single Pulsed (Note 3)	E _{AS}	109	mJ
Peak Diode Recovery dv/dt (Note 4)		dv/dt	1.9	ns
Power Dissipation	TO-220	0	156	W
	TO-220F1	P_D	51	W
Junction Temperature		TJ	+150	°C
Storage Temperature		T _{STG}	-55 ~ +150	°C

Notes: 1. Absolute maximum ratings are those values beyond which the device could be permanently damaged.

Absolute maximum ratings are stress ratings only and functional device operation is not implied.

- 2. Repetitive Rating: Pulse width limited by maximum junction temperature.
- 3. L = 10mH, I_{AS} = 4.69A, V_{DD} = 50V, R_G = 25 Ω , Starting T_J = 25 $^{\circ}$ C
- 4. $I_{SD} \le 12A$, di/dt $\le 200A/\mu s$, $V_{DD} \le BV_{DSS}$, Starting $T_J = 25^{\circ}C$

■ THERMAL DATA

PARAMETER		SYMBOL	RATING	UNIT	
Junction to Ambient		θ_{JA}	62.5	°C/W	
Junction to Case	TO-220	0	0.56	°C/W	
	TO-220F1	θ _{JC}	2.43	°C/W	

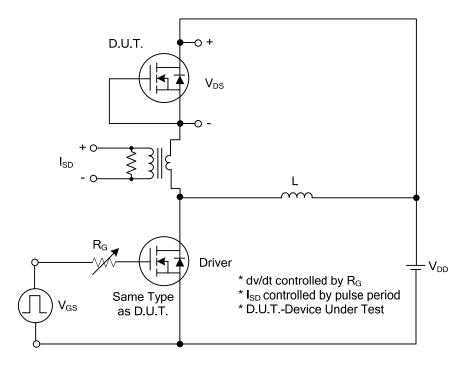
■ ELECTRICAL CHARACTERISTICS (T_J =25°C, unless otherwise specified)

PARAMETER		TEST CONDITIONS		TYP	MAX	UNI T
Drain-Source Breakdown Voltage		V _{GS} =0V, I _D =250μA				V
Drain-Source Leakage Current		V _{DS} =600V, V _{GS} =0V			1	μΑ
Forward	I _{GSS}	V_{GS} =30V, V_{DS} =0V			100	nΑ
Reverse		V_{GS} =-30V, V_{DS} =0V			-100	nΑ
Gate Threshold Voltage		$V_{DS}=V_{GS}$, $I_D=250\mu A$			4.0	٧
Static Drain-Source On-State Resistance		V _{GS} =10V, I _D =6.0A			0.7	Ω
_						
nput Capacitance				1465		pF
Output Capacitance		V_{GS} =0V, V_{DS} =25V, f =1.0 MHz		245		pF
Reverse Transfer Capacitance		1		57		pF
Total Gate Charge (Note 1)		\/ -50\/ -4.2A -400A		144		nC
Gate-Source Charge				10		nC
Gate-Drain Charge		V _{GS} -10V (Note 1,2)		27		nC
Turn-On Delay Time (Note 1)				81		ns
Turn-On Rise Time		V_{DD} =30V, I_{D} =0.5A,		152		ns
Turn-Off Delay Time		R _G =25Ω, V _{GS} =10V (Note 1,2)		430		ns
Turn-Off Fall Time						ns
TERISTIC	S AND MAXII	MUM RATINGS				
Maximum Continuous Drain-Source Diode					10	Α
Forward Current					12	A
Maximum Pulsed Drain-Source Diode					10	Α
Forward Current					40	۲
Drain-Source Diode Forward Voltage		V _{GS} =0 V, I _S =6.0 A			1.4	V
Reverse Recovery Time		V _{GS} =0 V, I _S =6.0 A, 33		336		ns
Reverse Recovery Charge		dI _F /dt=100 A/μs (Note 1)		2.21		μC
	ance FERISTIC Diode e	V _{GS(TH)}	$\begin{array}{c ccccccccccccccccccccccccccccccccccc$	$\begin{array}{c ccccccccccccccccccccccccccccccccccc$	$\begin{array}{c ccccccccccccccccccccccccccccccccccc$	BV _{DSS}

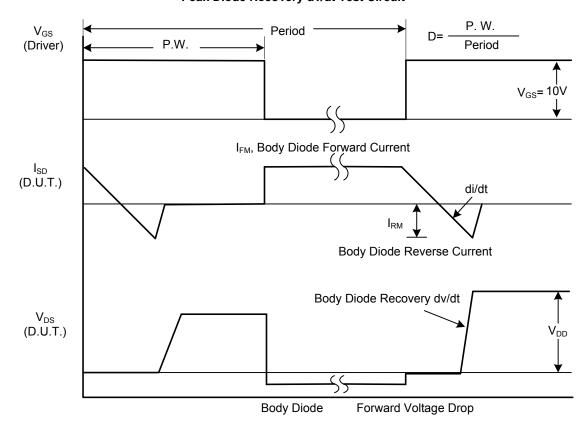
Notes: 1. Pulse Test: Pulse width \leq 300 μ s, Duty cycle \leq 2%.

^{2.} Essentially independent of operating temperature.

■ TEST CIRCUITS AND WAVEFORMS



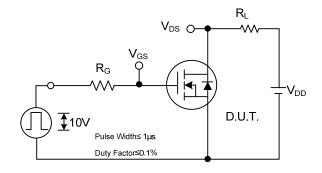
Peak Diode Recovery dv/dt Test Circuit

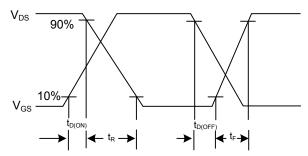


Peak Diode Recovery dv/dt Waveforms

12N60-C Power MOSFET

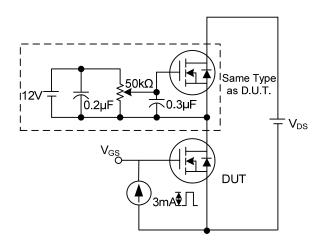
■ TEST CIRCUITS AND WAVEFORMS (Cont.)

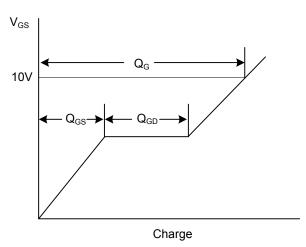




Switching Test Circuit

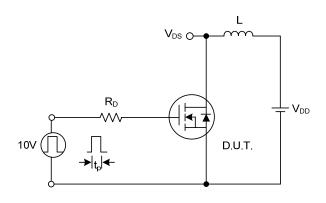
Switching Waveforms

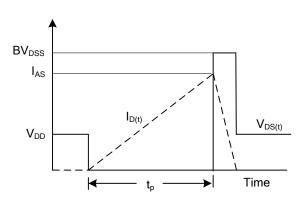




Gate Charge Test Circuit

Gate Charge Waveform





Unclamped Inductive Switching Test Circuit

Unclamped Inductive Switching Waveforms

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